

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
ASMMC.047AUSAPPLICATION NO.
10/601,037INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT
HuctariFILING DATE
June 19, 2003GROUP
2822

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	1	2003/0072975	04/2003	Shero et al.			

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EXAMINER	/Christy Novacek/	DATE CONSIDERED	08/10/2006
EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

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CN	1	6,368,954 B1	4/9/02	Lopatin et al.			
	2	6,407,435 B1	6/18/02	Ma et al.			
	3	6,482,740 B2	11/19/02	Soininen et al.			
	4	6,506,676 B2	1/14/03	Park et al.			
	5	6,511,876 B2	1/28/03	Buchanan et al.			
	6	6,518,106 B2	2/11/03	Ngai et al.			
	7	6,537,901 B2	3/25/03	Cha et al.			
	8	6,579,767 B2	6/17/03	Park et al.			
	9	6,596,576 B2	7/22/03	Fu et al.			
	10	6,627,503 B2	9/30/03	Ma et al.			
	11	6,696,332 B2	2/24/04	Visokay et al.			
	12	6,700,771 B2	3/2/04	Bhattacharyya			
	13	6,713,846 B1	3/30/04	Senzaki			
	14	6,714,435 B1	3/30/04	Dimmler et al.			
	15	6,717,226 B2	4/6/04	Hegde et al.			
	16	6,723,581 B1	4/20/04	Chabal et al.			
	17	6,730,163 B2	5/4/04	Vaarstra			
CN	18	6,730,588 B1	5/4/04	Schinella			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	19							

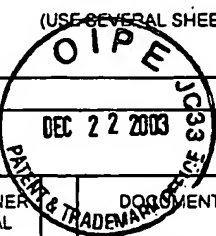
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

EXAMINER INITIAL	
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EXAMINER	/Christy Novacek/	DATE CONSIDERED	08/10/2006
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Hannu Huotari	
		FILING DATE June 19, 2003	GROUP ART UNIT 2811



U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
CN	5,625,217	04/29/97	Chau, et. al.				
	5,783,478	07/21/98	Chau, et. al.				
	6,066,533	05/23/00	Yu				
	6,166,417	12/26/00	Bai, et. al.				
	6,225,168 B1	05/01/01	Gardner, et. al.				
	6,265,258 B1	07/24/01	Liang, et. al.				
	6,291,282 B1	09/18/01	Wilk, et. al.				
	2001/0041250 A1	11/15/01	Werkhoven, et. al.				
	2002/0008257 A1	01/24/02	Barnak, et. al.				
	2002/0030235 A1	03/14/02	Agarwal, et. al.				
	6,373,111 B1	04/16/02	Zheng, et. al.				
	6,383,879	05/07/02	Kizilyalli, et. al.				
	2002/0096724 A1	07/25/02	Liang, et. al.				
	6,458,695 B1	10/01/02	Lin, et. al.				
	6,613,695 B2	09/02/03	Pomarede, et. al.				
CN	2003/0165615 A1	09/04/03	Aaltonen, et. al. Application Publication				

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
CN	EP 0 854 505 A2	07/22/98	European				
	WO 01/29892 A1	04/26/01	PCT				
	WO 01/29893 A1	04/26/01	PCT				
	WO 02/43115 A2	05/30/02	PCT				
CN	WO 94/14198	06/23/94	PCT				

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OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)							
EXAMINER INITIAL							
CN		Suntola, T., "Atomic Layer Epitaxy," Handbook of Crystal Growth 3, Thin Films and Epitaxy Part B: Growth Mechanisms and Dynamics, (1994) pp. 601-663.					

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